

Notice of References Cited	Application/Control No. 10/578,988	Applicant(s)/Patent Under Reexamination FUJIWARA ET AL.	
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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2001/0006149	07-2001	Taniike et al.	204/403
	B	US-			
	C	US-			
	D	US-			
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	F	US-			
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